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PATENT  
Customer No. 22,852  
Attorney Docket No. 3180.0285

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: )  
)  
KUNIHIRO MITSUTAKE ET AL. )  
)  
Serial No.: 09/931,916 ) Group Art Unit: 2857  
)  
Filed: August 20, 2001 ) Examiner: M. Baran  
)  
For: METHOD, APPARATUS, AND )  
COMPUTER PROGRAM OF )  
SEARCHING FOR CLUSTERING )  
FAULTS IN SEMICONDUCTOR )  
DEVICE MANUFACTURING )

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)**

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicants bring to the attention of the Examiner the document listed on the attached PTO 1449. This Information Disclosure Statement is being filed concurrently with a Request for Continued Examination for the above-referenced application.

A copy of the listed document is attached.

Applicants respectfully request that the Examiner consider the listed document and indicate that it was considered by making an appropriate notation on the attached form.

In lieu of a statement of relevance or translation of the non-English document, a Notification of the First Office Action issued by the Patent Office of the People's Republic of China in a corresponding Chinese application citing the document and

setting forth the relevance thereof is enclosed. In addition, an English-language translation of the Notification and English-language abstract of the document are provided.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that the listed document is material or constitutes "prior art." If the Examiner applies the document as prior art against any claim in the application and applicants determine that the cited document does not constitute "prior art" under United States law, applicants reserve the right to present to the office the relevant facts and law regarding the appropriate status of such document.

Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed document, should the document be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.


Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,  
GARRETT & DUNNER, L.L.P.

Dated: \_\_\_\_\_

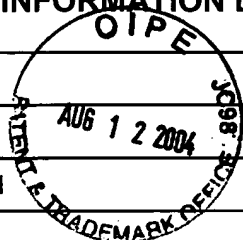
8/12/04

By: \_\_\_\_\_

  
Richard V. Burgujian  
Reg. No. 31,744

## INFORMATION DISCLOSURE CITATION

Atty. Docket No.	3180.0285	Appln. No.	09/931,916
Applicant	Mitsutake et al.		
Filing Date	August 20, 2001	Group:	2857



## U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate

## FOREIGN PATENT DOCUMENTS

Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
1207531	2/10/99	China			Abstract

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


Examiner	Date Considered
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	
Form PTO 1449	Patent and Trademark Office - U.S. Department of Commerce



PATENT  
Attorney Docket No. 3180.0285

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: )  
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FAULTS IN SEMICONDUCTOR )  
DEVICE MANUFACTURING )

**Mail Stop AF**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**REQUEST FOR INITIALED FORM PTO 1449**

An Information Disclosure Statement was filed in this application on August 20, 2001. In reviewing our file, we find that we have not received from your Office a copy of the Form PTO-1449 which would serve as acknowledgment of receipt of the Information Disclosure Statement and as an indication that the references were considered by the examiner.

Copies of the Information Disclosure Statement, the Information Disclosure Citation on Form PTO-1449, and the postcard that was filed with the Information Disclosure Statement and was stamped by the U.S. Patent and Trademark Office to indicate receipt of the papers, are attached.

The Examiner is respectfully requested either to send us a duplicate of the copy of the Form PTO-1449 or issue a Supplemental Notice of Allowability (PTOL-37) which both acknowledges receipt of the Information Disclosure Statement and the Information Disclosure Citation, and indicates that the references were considered by the Examiner.

If there are any fees due in connection with the filing of this Request, please charge the fees to Deposit Account No. 06-0916.

Respectfully submitted,

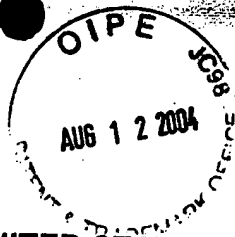
FINNEGAN, HENDERSON, FARABOW,  
GARRETT & DUNNER, L.L.P.

Dated: \_\_\_\_\_

8/12/04

By: \_\_\_\_\_

Richard V. Burgujian  
Reg. No. 31,744



Attorney Docket No.: 03180.0285  
Customer Number: 22,852

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: )  
Kunihiro MITSUTAKE et al. )  
Serial No.: Not yet assigned ) Group Art Unit: Not assigned  
Filed: August 20, 2001 ) Examiner: Not assigned

For: METHOD, APPARATUS, AND COMPUTER PROGRAM OF SEARCHING  
FOR CLUSTERING FAULTS IN SEMICONDUCTOR DEVICE MANUFACTURING

Assistant Commissioner for Patents  
Washington, DC 20231

Sir:

**INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)**

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicants bring to the Examiner's attention the document listed on attached Form PTO-1449. A copy of the listed document is attached. Applicants respectfully request that the Examiner consider the document listed on attached Form PTO-1449 and indicate that it was considered by making an appropriate notation on this form.

This Information Disclosure Statement is being filed with the above-referenced application.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that the listed document is material or constitutes "prior art." If the Examiner applies the document as prior art against any claim in the application and applicants determine that the cited document does not constitute "prior art" under United States law, applicants

reserve the right to present to the office the relevant facts and law regarding the appropriate status of such document.

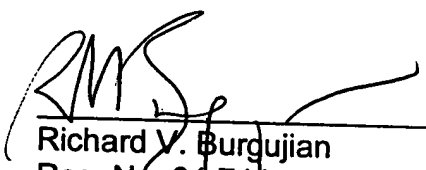
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If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,  
GARRETT & DUNNER, L.L.P.

By:

  
Richard V. Burgujian  
Reg. No. 31,744

Dated: August 20, 2001

Enclosures  
RVB/FPD/dvz

LAW OFFICES  
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WASHINGTON, DC 20005  
202-462-4000

AUG 12 2004

OMB No. 0651-0011

# **INFORMATION DISCLOSURE CITATION** (Use several sheets if necessary)

Atty. Docket No. 03180.0285				Serial No. Not Yet Assigned			
Applicant Kunihiro MITSUTAKE et al.							
Filing Date August 20, 2001				Group			
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial*		Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Sub Class	Translation Yes or No
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
		IKOTA, M. et al., "Discrimination of Clustered Defects on Wafers Using Statistical Methods", Proc. 1997 Second Int. Workshop Statistical Metrology, pp. 52-55.					
Examiner				Date Considered			
*Examiner:		Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					
Form PTO 1449				Patent and Trademark Office - U.S. Department of Commerce			



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